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EXPEDITED PROCEDURE - 2829

AUG 11 2005

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| To: Examiner Jimmy Nguyen | Total Pages Sent: 6 |
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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|-------------|---|-------------|-----------------|
| Applicant: | Schneegans, et al. | Docket No.: | 2001 P 17353 US |
| Serial No: | 10/826,954 | Art Unit: | 2829 |
| Date Filed: | April 15, 2004 | | |
| Title: | Probe Needle for Testing Semiconductor Chips and Method for Producing Said Probe Needle | | |

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- Certification of Facsimile Transmission (1 page)
- Response After Final Rejection (5 pages)

Respectfully submitted,


AnneMarie James
Legal Assistant**Confirmation Respectfully Requested**

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Mail Stop: AF
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

RESPONSE AFTER FINAL REJECTION

Dear Sir:

The following remarks are presented in response to the Examiner's Office Action mailed June 13, 2005. In view of these remarks, withdrawal of the rejection and allowance of the claims is respectfully requested.